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Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet 1 of 1

Complete if Known

Application Number	10/630,970
Filing Date	07/31/2003
First Named Inventor	DAVID L O'MEARA
Art Unit	2818
Examiner Name	Phuc Dang
Attorney Docket Number	071469-0303786

U. S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
PD	1	US- 6,258,731 B1	07-10-2001	ANDO	
↓	2	US- 2001/0102859 A1	08-01-2002	YOO	
↓	3	US- 5,296,412	03-22-1994	OHSAWA	
PD	4	US- 2002/111001 A1	08-15-2002	AHN et al.	
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ Number ⁴ Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶

Examiner
Signature

PHUC T. DANG

Date
Considered

9/1/05

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Substitute for form 1449B/PTO		Complete if Known			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	10/630,970		
		Filing Date	07/31/2003		
		First Named Inventor	DAVID L O'MEARA		
		Art Unit	2818		
		Examiner Name	Phuc Dang		
Sheet	1	of	1	Attorney Docket Number	071469-0303786

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
PD	I	J. DERRIEN, "SiO ₂ Ultra Thin Film Growth Kinetics as Investigated by Surface Techniques," Surface Science, North-Holland Publishing Company, pp. 32-46, (June 1982).	
PD	II	C. RAISIN ET AL., "Work Function Measurements During Growth of Ultra Thin Films of SiO ₂ on Characterized Silicon Surfaces," Solid-State Electronics, Pergamon Press Ltd., Vol. 27 (No. 5), pp. 413-417, (May 1984).	
PD	III	MAHISHA KUNDU ET AL., "Effect of oxygen pressure on the structure and thermal stability of ultrathin Al ₂ O ₃ films on Si (001)," Journal of Applied Physics, American Institute of Physics, Vol. 91 (No. 1), pp. 492-500, (January 1, 2002).	

Examiner Signature	PHUC T. DANG	Date Considered	9/1/05
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¹Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached. This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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